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IAP20 REC'D 23 JAN 2006
TPO-5168

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Ken MURAYAMA, et al

Serial No.: not yet assigned

Filed: January 23, 2006

For: PROBE REPLACEMENT METHOD FOR SCANNING PROBE
MICROSCOPE

Group: not yet assigned

Examiner: not yet assigned

**INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR §1.97 & 1.98**

MS Amendment

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

January 23, 2006

Sir:

In the matter of the above-identified application, applicants are submitting herewith a copy of a communication from a foreign patent office in a counterpart foreign application and copies of the documents listed in the attached form equivalent to Form PTO-1449 for the Examiner's consideration.

This information disclosure statement is being submitted with the new application.

The documents listed on the attached form equivalent to Form PTO-1449 are not in the English language, the requirement of 37 CFR §1.98(a)(3) for a concise explanation of the relevance is satisfied by the attached English language abstracts.

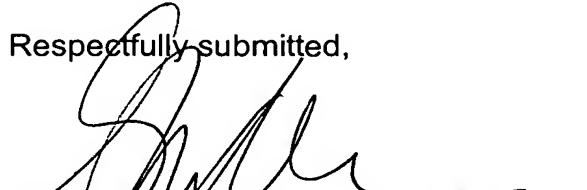
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It is respectfully requested that this information disclosure statement be considered by the Examiner.

Please charge any shortage in the fees due in connection with the filing of this paper, including extension of time fees, to the deposit account of MATTINGLY, STANGER, MALUR & BRUNDIDGE, P.C., Deposit Account No. 50-1417 (TPO-5168) please credit any excess fees to such deposit account.

Respectfully submitted,



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Form PTO- 1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DKT. NO. TPO-5168	SERIAL NO. NOT YET ASSIGNED 201365509
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)		APPLICANT Ken MURAYAMA, et al	
		FILING DATE January 23, 2006	GROUP Not Yet Assigned

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
AA						
AB						
AC						
AD						
AE						
AF						
AG						
AH						
AI						
AJ						
AK						
AL						

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Abstract	
						Yes	No
AM	10-104245	04/98	JP			X	
AN	10-267948	10/98	JP			X	
AO	2000-329772	11/00	JP			X	
AP	2002-323426	11/02	JP			X	
AQ	97/08733	3/97	WO			X	
AR							
AS							
AT							

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

AU	
AV	
AW	
AX	
AY	
AZ	
Examiner	Date Considered